

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. M122-1372		SERIAL NO. 09/927,230	
<div style="text-align: center;"> STATE OF THE ART CITED BY APPLICANT (Use several sheets if necessary) MAILED DATE CANCELLED </div>				APPLICANT Trung Tri Doan			
				FILING DATE August 9, 2001		GROUP 1762	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6270572	08/2001	Kim et al	117	93	
	AB	6083832	07/2000	Sugai	438	672	
	AC	4369105	01/1983	Caldwell et al	204	290 F	
	AD	4831003	05/1989	Lang et al	502	182	
	AE	6287965	09/2001	Kang et al	438	648	
	AF	5480818	01/1996	Matsumoto et al	437	40	
	AG	6203613	03/2001	Gates et al	117	104	
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AJ						Yes No
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Form PTO-1349		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1372		SERIAL NO. 09/927,330	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Trang Thi Doan		FILING DATE August 9, 2001	
				GROUP 1761			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AJ	05251339	02-1993	JAPAN			
	AK						
	AL						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER				DATE CONSIDERED			
				10/16/02			
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2 Sheet 1 of 2

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ATTY. DOCKET NO.
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APPLICANT
Trung Tri Doan

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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	5,270,247	12/1993	Sakuma et al.			
AB						
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FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation	
					Yes	No
AJ	EP 0 794 568	10/09/97	Europe	H01L	21/768	X
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AM	Noah Precision, Inc., Internet website: http://www.noahprecision.com/tec.htm ; "Thermoelectric Temperature Control" 1998, pps. 1-2.
AN	Noah Precision, Inc., Internet website: http://www.noahprecision.com/cvd.htm ; "CVD" 1998, pps. 1-2.
AO	Kiyoko et al., Patent Abstract Application No. 04-024917 (JP 9224917, 09/1993), "Semiconductor Substrate and Its Manufacture."
AP	Ritala, et al., "Atomic Layer Epitaxy - A Valuable Tool for Nanotechnology?" Nanotechnology, Vol. 10, No. 1, pps. 19-24, March 1999.
AQ	George, et al., "Surface Chemistry for Atomic Layer Growth", Journal of Physical Chemistry, Vol. 100, No. 31, pps. 13121-13131, August 1, 1996.
AR	Suntola, "Atomic Layer Epitaxy", Handbook of Crystal Growth, Vol. 3, Chapter 14, pps. 602-663, 1994.
AS	Vernon, S.M., "Low-cost, high-efficiency solar cells utilizing GaAs-on-Si technology." Dialog Abstract of Report No. NREL/TP-451-5353; 04/1993.

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Trung Tri Doan			
					FILING DATE Herewith		GROUP Unassigned	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	09/643,004		Mercaldi			08/21/2000	
	AB	09/619,449		Derderian			07/19/2000	
	AC	09/652,533		Derderian			08/31/2000	
	AD							
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	AG							
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	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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M122-1372SERIAL NO.
09/927,230LIST OF ART CITED BY APPLICANT
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APPLICANT Trung Tri Doan

FILING DATE
August 9, 2001GROUP
1762

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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA		5,985,770	11/1999	Sandhu et al			
AB		5,281,274	1/1994	Yoder			
AC		5,368,555	11/1994	Kelly			
AD		5,413,671	5/1995	Ketchum			
AE		5,747,113	5/1998	Tsai			
AF		6,306,216	10/2001	Kim et al			
AG		5,116,840	5/1992	Mikami et al			
AH							
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

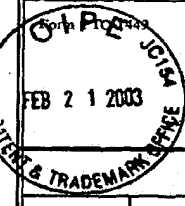

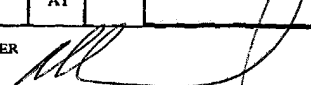

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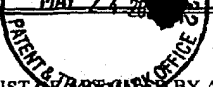
EV317136005

		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1372		SERIAL NO. 09/927,230	
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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	AA	4,913,090	04/1990	Harada et al			
	AB	6,307,184	10/2001	Womack et al			
	AC	5,616,208	04/1997	Lee			
	AD	6,203,618	03/2001	McMillan			
	AE	5,462,603	10/1995	Murakami			
	AF	6,399,921	06/2002	Johnsgard et al			
	AG	5,997,588	12/1999	Goodwin et al			
	AH	3,785,853	01/1974	Kirkman et al			
	AI	6,139,695	10/2000	Washburn et al			
	AJ	6,355,561	03/2002	Sandhu et al			
	AK	6,335,561	01/2002	Imoto			
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AP		Aarik, et al, "Control of Thin Film Structure by Reactant Pressure in Atomic Layer Deposition of TiO_2 ", Journal of Crystal Growth, 169 (1996) pgs. 496-502				
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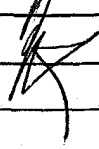
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1372		SERIAL NO. 09/927,230	
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,479,902	11/2002	Lopatin et al			
	AB	6,458,416	10/2002	Derderian et al			
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	AD	6,235,871	05/2001	Doan			
	AE	6,066,358	05/2000	Guo			
	AF	5,366,953	11/1994	Char et al			
	AG	5,273,930	12/1993	Steele et al			
	AH	6,114,099	09/2000	Liu et al			
	AI	2002/0125516	09/2002	Marsh et al			
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
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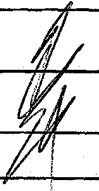
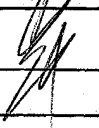
EV085426511

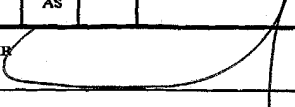
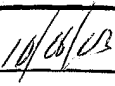


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	AA	6,174,377	01-2001	Doering et al			
	AB	5,916,365	06-1999	Sherman			
	AC						
	AD						
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	AM	Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level", Applied Surface Science, vol. 100/101, March 1996, pp. 391-398.
	AN	Aarik et al, "Effect of Growth Conditions on Formation of TiO2-II Thin Films in Atomic Layer Deposition Process", Journal of Crystal Growth, Vol. 181, August 1997, pp. 259-264.
	AO	Skarp, "ALE-Reactor for Large Area Depositions", Applied Surface Science, vol. 112, March 1997, pp. 251-254.
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